Notice of References Cited Application/Control No. 10/825,445 Examiner Anthony Weier Applicant(s)/Patent Under Reexamination SHEN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0258827	12-2004	Shen, Cheng	426/598
	В	US-2005/0202147	09-2005	Wong et al.	426/598
	С	US-4,039,696	08-1977	Marquardt et al.	. 426/598
	D	US-5,658,609	08-1997	Abboud et al.	426/609
	Е	US-6,861,080	03-2005	Kent et al.	426/36
	F	US-6,303,160	10-2001	Laye et al.	426/36
	G	US-			
	H	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0		:			
	Р					
	Q					
	R				·	
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	x					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.